

ABSTRACT

CANTILEVER-TYPE PROBE MECHANISM AND METHOD OF MAKING CANTILEVER-TYPE PROBE CARD

A cantilever-type probe mechanism for transmitting high frequency signal includes a probe pin holder, a transmission line, at least one metal signal pin and at least one metal grounding pin. The metal signal pin has a mounting portion mounted to
5 the probe pin holder and electrically connected with a metal core of the transmission line, a probing tip for probing an electronic component on a wafer, and a front arm integrally extending from the mounting portion to the probing tip. The metal grounding pin has a mounting portion mounted to the probe pin holder and electrically connected with a metal layer spacedly surrounding the metal core, a probing tip, and a front arm
10 spaced from the front arm of the at least one metal signal pin for maintaining the characteristic impedance of the signal pin upon transmitting high frequency test signal.

FIGURE 3